

Search Notes		Application/Control No.	Applicant(s)/Patent under Reexamination
		10/735,908	HAN ET AL.
		Examiner	Art Unit
		Tran N. Nguyen	2834

SEARCHED			
Class	Subclass	Date	Examiner
310	211 156.08	2/28/05	TNN
	156.12		
310	156.23	3/2/05	TNN
	156.26		
	156.28		
	156.29		
	166		
310	156.81	3/3/05	TNN
update all above 9/13/05 TNN			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner